

Search Notes				Application/Control No.	Applicant(s)/Patent under Reexamination
				10/056,080	SHIN-ICHIROU HARASAWA
				Examiner	Art Unit
				Tran Q. Le	2633

SEARCHED			
Class	Subclass	Date	Examiner
398	6,11,18	2/11/2005	TQL
"	23,32,33	2/11/2005	TQL
"	37,38,62	2/11/2005	TQL
"	64,97,157	2/11/2005	TQL
"	160,177	2/11/2005	TQL
359	333-349	2/14/2005	TQL
372	70,71	2/16/2005	TQL
	82,83,88	2/16/2005	TQL
ABOVE UPDATED	SEARCH	8/4/05	DS

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Jason C.	2/11/2005	TQL
Inventor check	2/11/2005	TQL
EAST (US-PGPUB; USPAT; EPO; JPO) See Search Results Printout	8/4/05	DS